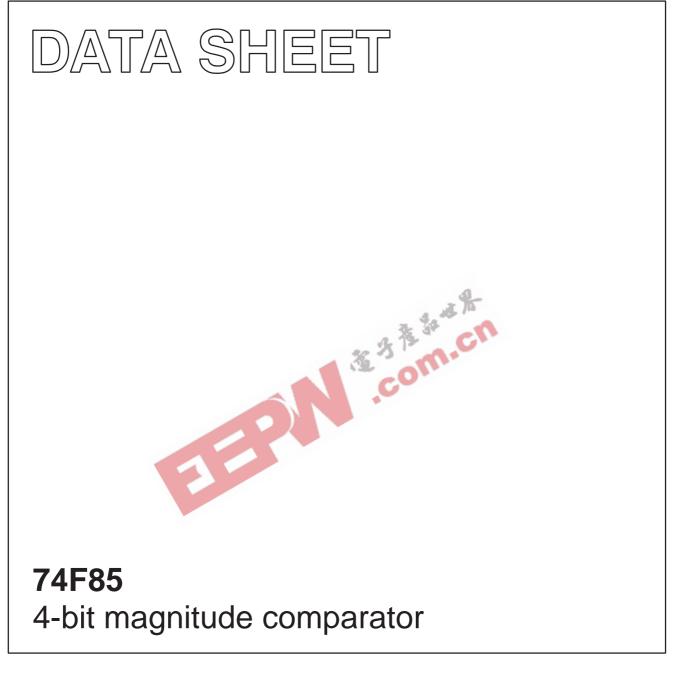
INTEGRATED CIRCUITS



Product specification

1994 Sep 27

IC15 Data Handbook

Philips Semiconductors





74F85

FEATURES

- High-impedance NPN base inputs for reduced loading (20µA in High and Low states)
- Magnitude comparison of any binary words
- Serial or parallel expansion without extra gating

DESCRIPTION

The 74F85 is a 4-bit magnitude comparator that can be expanded to almost any length. It compares two 4-bit binary, BCD, or other monotonic codes and presents the three possible magnitude results at the outputs. The 4-bit inputs are weighted (A0-A3) and (B0-B3) where A3 and B3 are the most significant bits. The operation of the 74F85 is described in the Function Table, showing all possible logic conditions. The upper part of the table describes the normal operation under all conditions that will occur in a single device or in a series expansion scheme. In the upper part of the table the three outputs are mutually exclusive. In the lower part of the table, the outputs reflect the feed-forward conditions that exist in the parallel expansion scheme. The expansion inputs $I_{A>B}$, and $I_{A=B}$ and $I_{A<B}$ are the least significant bit positions. When used for series expansion, the A>B, A=B and A<B outputs of the lease significant word are connected to the corresponding $I_{A>B},\,I_{A=B}$ and $I_{A<B}$ inputs of the next higher stage. Stages can be added in this manner to any length, but a propagation delay penalty of about 15ns is added with each additional stage. For proper operation, the expansion inputs of the least significant word should be tied as follows: IA>B = Low $I_{A=B} = High$, and $I_{A<B} = Low$.

INPUT AND OUTPUT LOADING AND FAN OUT TABLE

B3 1 16 V_{CC} I_{A<B} 2 15 A3 14 B2 I_{A=B} 3 13 A2 4 IA>B 12 A1 A>B 5 11 B1 A=B 6 10 A0 A<B 7 9 B0 GND 8 SF00075

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F85	7.0ns	40mA

ORDERING INFORMATION

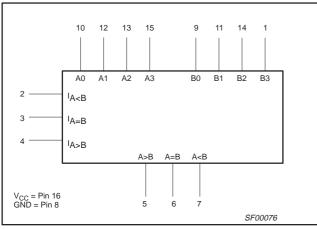
PIN CONFIGURATION

DESCRIPTION	$\begin{array}{l} \mbox{COMMERCIAL RANGE} \\ \mbox{V}_{CC} = 5V \pm 10\%, \\ \mbox{T}_{amb} = 0^\circ \mbox{C to } + 70^\circ \mbox{C} \end{array}$	PKG DWG #
16-pin plastic DIP	N74F85N	SOT38-4
16-pin plastic SO	N74F85D	SOT162-1

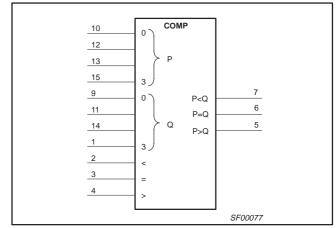
PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
A0–A3	Comparing inputs	1.0/0.033	20μΑ/20μΑ
B0–B3	Comparing inputs	1.0/0.033	20μΑ/20μΑ
I _{A<b< sub="">, I_{A=B}, I_{A>B}</b<>}	Expansion inputs (active High)	1.0/0.033	20μΑ/20μΑ
A <b, a="">B</b,>	Data outputs (active High)	50/33	1.0mA/20mA

NOTE: One (1.0) FAST unit load is defined as: 20µA in the High state and 0.6mA in the Low state.

LOGIC SYMBOL

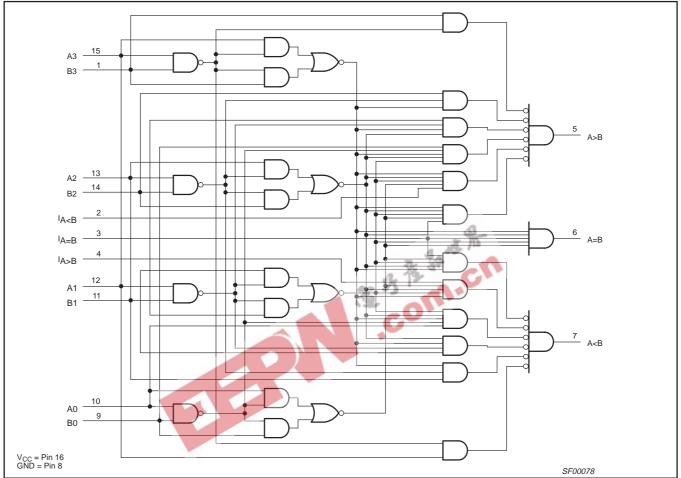


IEC/IEEE SYMBOL



74F85

LOGIC DIAGRAM



FUNCTION TABLE

	COMPARIN	NG INPUTS		EXI		UTS		OUTPUTS	
A3,B3	A2,B2	A1,B1	A0,B0	I _{A>B}	I _{A<b< sub=""></b<>}	I _{A=B}	A>B	A <b< th=""><th>A=B</th></b<>	A=B
A3>B3	Х	Х	Х	Х	Х	Х	Н	L	L
A3 <b3< td=""><td>Х</td><td>Х</td><td>Х</td><td>Х</td><td>Х</td><td>Х</td><td>L</td><td>Н</td><td>L</td></b3<>	Х	Х	Х	Х	Х	Х	L	Н	L
A3=B3	A2>B2	Х	Х	Х	Х	Х	н	L	L
A3=B3	A2 <b2< td=""><td>Х</td><td>Х</td><td>Х</td><td>Х</td><td>Х</td><td>L</td><td>Н</td><td>L</td></b2<>	Х	Х	Х	Х	Х	L	Н	L
A3=B3	A2=B2	A1>B1	Х	Х	Х	Х	н	L	L
A3=B3	A2=B2	A1 <b1< td=""><td>Х</td><td>Х</td><td>Х</td><td>Х</td><td>L</td><td>Н</td><td>L</td></b1<>	Х	Х	Х	Х	L	Н	L
A3=B3	A2=B2	A1=B1	A0>B0	Х	Х	Х	н	L	L
A3=B3	A2=B2	A1=B1	A0 <b0< td=""><td>Х</td><td>Х</td><td>Х</td><td>L</td><td>Н</td><td>L</td></b0<>	Х	Х	Х	L	Н	L
A3=B3	A2=B2	A1=B1	A0=B0	Н	L	L	Н	L	L
A3=B3	A2=B2	A1=B1	A0=B0	L	Н	L	L	Н	L
A3=B3	A2=B2	A1=B1	A0=B0	L	L	Н	L	L	Н
A3=B3	A2=B2	A1=B1	A0=B0	Х	Х	Н	L	L	Н
A3=B3	A2=B2	A1=B1	A0=B0	н	Н	L	L	L	L
A3=B3	A2=B2	A1=B1	A0=B0	L	L	L	н	Н	L

H = High voltage level L = Low voltage level X = Don't care

74F85

APPLICATION

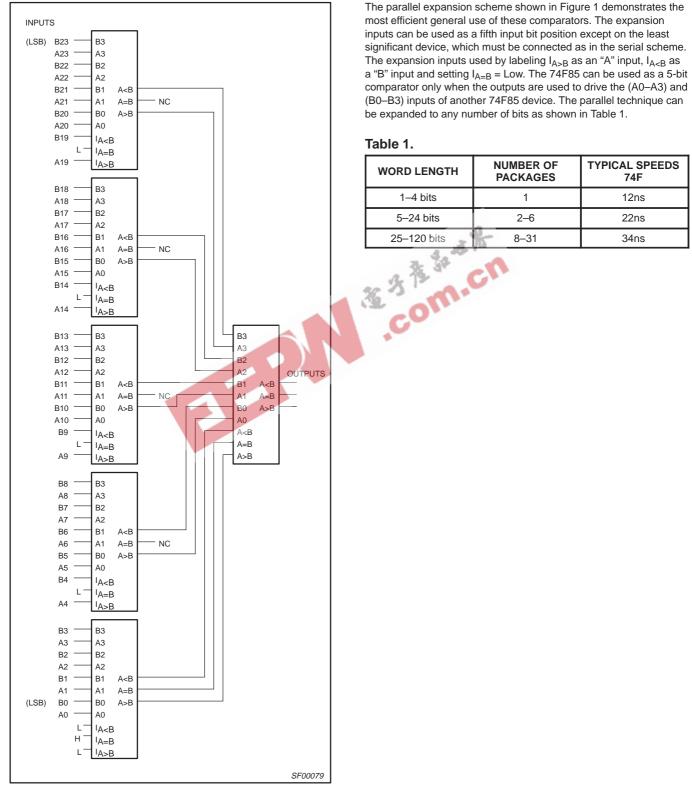


Figure 1. Comparison of Two 24-Bit Words

74F85

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage	-0.5 to +7.0	V
V _{IN}	Input voltage	-0.5 to +7.0	V
I _{IN}	Input current	-30 to +5	mA
V _{OUT}	Voltage applied to output in High output state	–0.5 to V_{CC}	V
I _{OUT}	Current applied to output in Low output state	40	mA
T _{amb}	Operating free-air temperature range	0 to +70	°C
T _{stg}	Storage temperature range	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER		LIMITS				
STWBOL	PARAMETER	MIN	NOM	MAX	UNIT		
V _{CC}	Supply voltage	4.5	5.0	5.5	V		
V _{IH}	High-level input voltage	2.0			V		
V _{IL}	Low-level input voltage	0		0.8	V		
I _{IK}	Input clamp current			-18	mA		
I _{OH}	High-level output current			-1	mA		
I _{OL}	Low-level output current			20	mA		
T _{amb}	Operating free-air temperature range	0		+70	°C		

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

CVMDOI	PADAMETED		TEST		NC1		UNIT		
SYMBOL	PARAMETER	TEST CONDITIONS ¹			MIN	TYP ²	MAX	UNIT	
Maria			$V_{CC} = MIN, V_{IL} = N$	1AX	$\pm 10\% V_{CC}$	2.5			V
V _{OH}	High-level output voltage		$V_{IH} = MIN, I_{OH} = M$	AX	$\pm 5\% V_{CC}$	2.7	3.4		v
Max		$V_{CC} = MIN, V_{IL} = N$	1AX	$\pm 10\% V_{CC}$		0.30	0.50	V	
V _{OL}	Low-level output voltage		$V_{IH} = MIN, I_{OL} = MAX$ $\pm 5\% V_{CC}$			0.30	0.50	v	
V _{IK}	Input clamp voltage		$V_{CC} = MIN, I_I = I_{IK}$				-0.73	-1.2	V
lj –	Input current at maximum input vo	oltage	$V_{CC} = 0.0V, V_1 = 7.0V$					100	μΑ
I _{IH}	High-level input current		$V_{CC} = MAX, V_I = 2.7V$					20	μA
IIL	Low-level input current		$V_{CC} = MAX, V_I = 0.5V$					-20	μA
I _{OS}	Short-circuit output current ³		$V_{CC} = MAX$	V _{CC} = MAX		-60		-150	mA
		I _{CCH}		V	_N = GND		36	50	
I _{CC}	Supply current (total)		V _{CC} = MAX	An = Bn I _{A>B} =	= I _{A=B} = GND, : I _{A<b< sub=""> = 4.5V</b<>}		40	54	mA

NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

2. All typical values are at $V_{CC} = 5V$, $T_{amb} = 25^{\circ}C$.

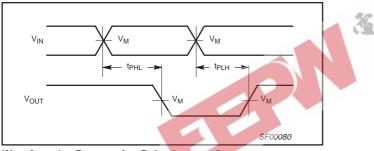
^{3.} Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

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AC ELECTRICAL CHARACTERISTICS

					LIMI	ſS		
SYMBOL	PARAMETER	TEST CONDITION	T _a	/ _{CC} = +5.0 1 _{mb} = +25° i0pF, R _L =	D ^o	V _{CC} = +5. T _{amb} = 0°0 C _L = 50pF,	UNIT	
			MIN	TYP	MAX	MIN	MAX	
t _{PLH} t _{PHL}	Propagation delay A or B to A <b, a="">B</b,>	Waveform 1 3 logic levels	6.0 7.0	8.5 9.5	11.0 14.0	5.5 6.5	13.0 15.5	ns
t _{PLH} t _{PHL}	Propagation delay A or B to A=B	Waveform 1 4 logic levels	6.5 7.0	9.0 9.5	11.5 14.0	6.0 6.5	14.0 14.5	ns
t _{PLH} t _{PHL}	Propagation delay $I_{A < B}$ and $I_{A=B}$ to $A > B$	Waveform 1 1 logic level	3.0 3.0	5.0 6.0	7.5 9.0	2.5 2.5	9.0 10.0	ns
t _{PLH} t _{PHL}	Propagation delay I _{A=B} to A=B	Waveform 1 2 logic levels	2.5 3.5	4.5 7.5	7.0 10.0	2.0 2.5	9.0 12.0	ns
t _{PLH} t _{PHL}	Propagation delay $I_{A>B}$ and $I_{A=B}$ to A <b< td=""><td>Waveform 1 1 logic level</td><td>3.0 3.0</td><td>5.0 6.0</td><td>8.0 9.0</td><td>3.0 2.0</td><td>9.5 9.5</td><td>ns</td></b<>	Waveform 1 1 logic level	3.0 3.0	5.0 6.0	8.0 9.0	3.0 2.0	9.5 9.5	ns
AC WAVE			3.0 3.0	om	.cn			

AC WAVEFORMS

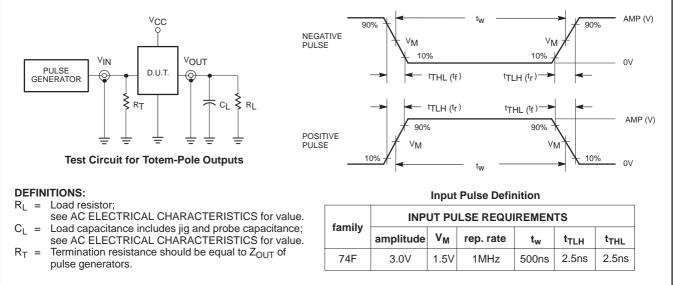


Waveform 1. Propagation Delay Input to Output

NOTE:

For all waveforms, $V_M = 1.5V$.

TEST CIRCUIT AND WAVEFORMS



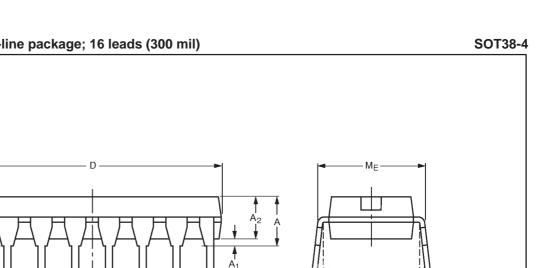
SF00006

seating plane

16

pin 1 index

4-bit magnitude comparator



 Φ WM

E

10 mm

 M_{H}

DIP16: plastic dual in-line package; 16 leads (300 mil)

DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	b ₂	с	D ⁽¹⁾	E ⁽¹⁾	е	e ₁	L	M _E	M _H	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	1.25 0.85	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	0.76
inches	0.17	0.020	0.13	0.068 0.051	0.021 0.015	0.049 0.033	0.014 0.009	0.77 0.73	0.26 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.030

5 scale 8

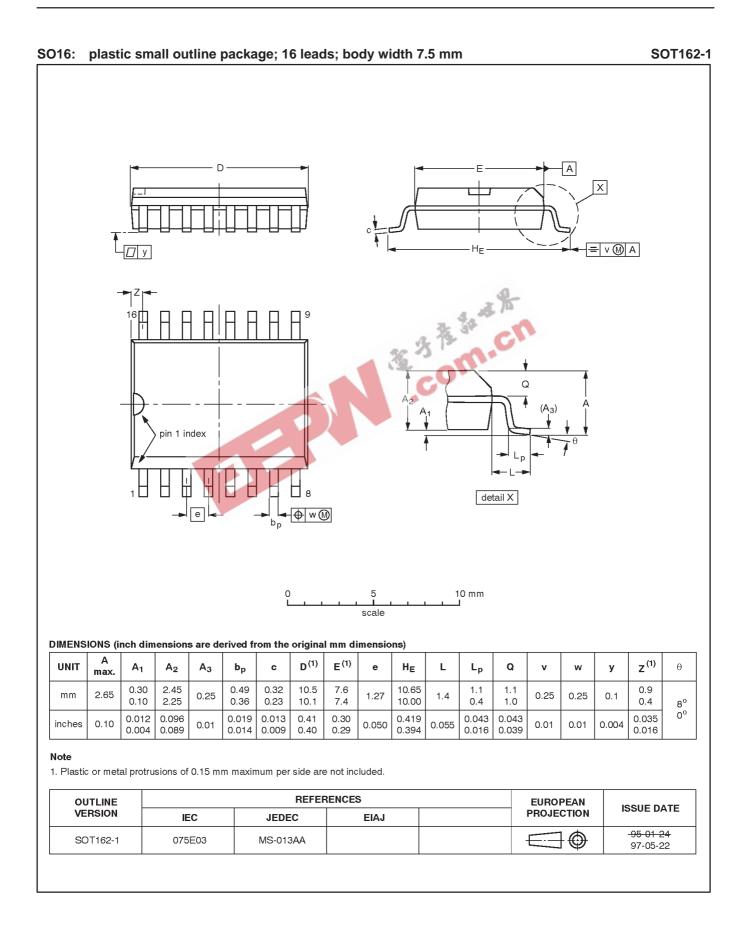
Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	RENCES			
VERSION	IEC	JEDEC	EIAJ	PROJECTION	ISSUE DATE	
SOT38-4					-92-11-17 95-01-14	

Product specification

74F85



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NOTES



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Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

[1] Please consult the most recently issued datasheet before initiating or completing a design.

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